| | | Application/Control No. | Applicant(s)/Patent Under Reexamination |
|---|---|---|---|
| **Notice of References Cited** | | 10/736,455 | METAXAS ET AL. |
| | | Examiner | Art Unit | |
| | | Max Shikhman | 2609 | Page 1 of 1 |

### U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|---|---|---|---|
| * | A | US-5,081,689 A | 01-1992 | Meyer et al. | 382/199 |
| * | B | US-5,239,596 A | 08-1993 | Mahoney, James V. | 382/180 |
| * | C | US-5,669,382 A | 09-1997 | Curwen et al. | 600/425 |
| * | D | US-6,078,680 A | 06-2000 | Yoshida et al. | 382/128 |
| * | E | US-6,138,045 A | 10-2000 | Kupinski et al. | 600/425 |
| * | F | US-6,249,594 B1 | 06-2001 | Hibbard, Lyn | 382/128 |
| * | G | US-2001/0044576 A1 | 11-2001 | Vining, David J. | 600/416 |
| * | H | US-6,385,332 B1 | 05-2002 | Zahalka et al. | 382/128 |
| * | I | US-6,591,004 B1 | 07-2003 | VanEssen et al. | 382/154 |
| * | J | US-2003/0156748 A1 | 08-2003 | Fang et al. | 382/145 |
| * | K | US-6,690,816 B2 | 02-2004 | Aylward et al. | 382/128 |
| * | L | US-6,909,913 B2 | 06-2005 | Vining, David J. | 600/407 |
| * | M | US-7,187,800 B2 | 03-2007 | Hibbard, Lyndon S. | 382/173 |

### FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|---|---|---|---|---|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

### NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| * | U | Rafael C. Gonzalez, Digital Image Processing, 11/09/2001, Prentice Hall, 2/E, p79,p245 |
| * | V | Kinnard, Separation of malignant and benign masses using maximum-likelihood modeling and neural networks, May 2002, SPIE, Volume 4684, pp. 733-741 |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.